New Direct-Product Testers and 2-Query PCPs

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Abstract

The "direct product code" of a function f gives its values on all k-tuples $(f(x_1), \ldots, f(x_k))$. This basic construct underlies "hardness amplification" in cryptography, circuit complexity and PCPs. Goldreich and Safra [GS00] pioneered its local testing and its PCP application. A recent result by Dinur and Goldenberg [DG08] enabled for the first time testing proximity to this important code in the "list-decoding" regime. In particular, they give a 2-query test which works for polynomially small success probability $1/k^{\alpha}$, and show that no such test works below success probability 1/k.

Our main result is a 3-query test which works for exponentially small success probability $\exp(-k^{\alpha})$. Our techniques (based on recent simplified decoding algorithms for the same code [IJKW08]) also allow us to considerably simplify the analysis of the 2-query test of [DG08]. We then show how to derandomize their test, achieving a code of polynomial rate, independent of k, and success probability $1/k^{\alpha}$.

Finally we show the applicability of the new tests to PCPs. Starting with a 2-query PCP over an alphabet Σ and with soundness error $1-\delta$, Rao [Rao08] (building on Raz's (k-fold) parallel repetition theorem [Raz98] and Holenstein's proof [Hol07]) obtains a new 2-query PCP over the alphabet Σ^k with soundness error $\exp(-\delta^2 k)$. Our techniques yield a 2-query PCP with soundness error $\exp(-\delta\sqrt{k})$; this is incomparable to Rao's result [Rao08] since our bound also applies when $k < 1/\delta$. Our PCP construction turns out to be essentially the same as the miss-match proof system defined and analyzed by Feige and Kilian [FK00], but with simpler analysis and exponentially better soundness error.

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